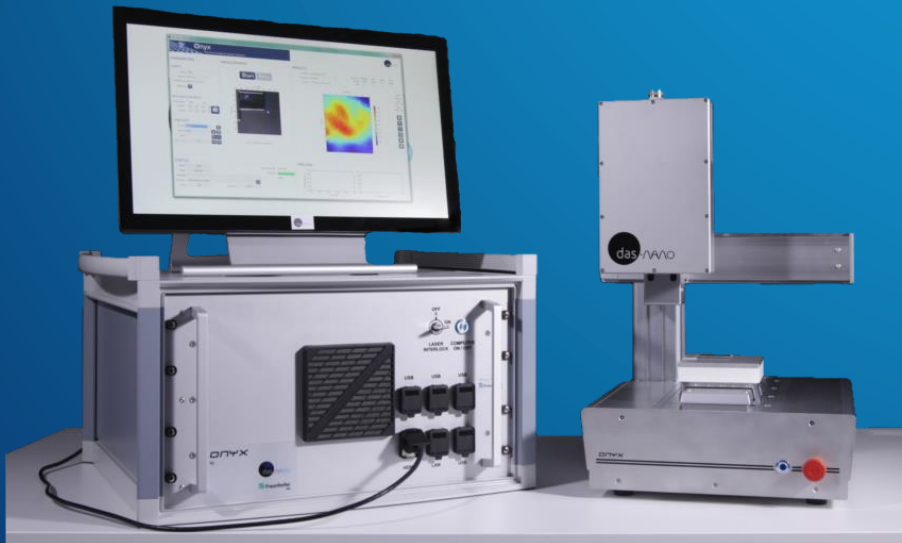




Onyx



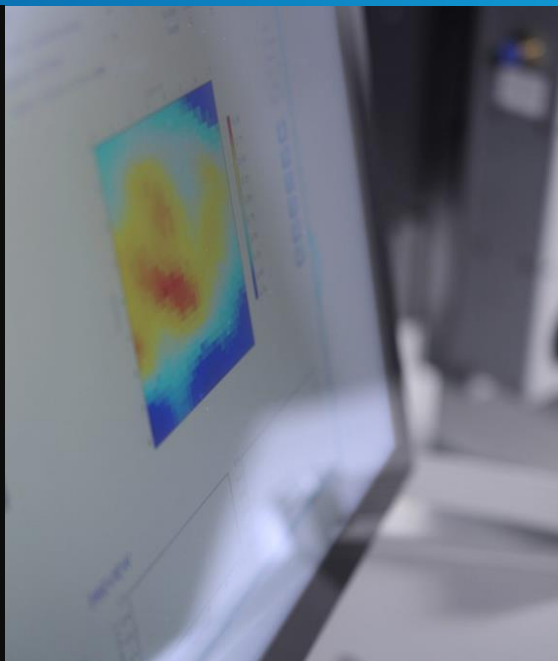
Graphene and 2D materials characterization

Onyx

Ultra-fast graphene and 2D materials characterization

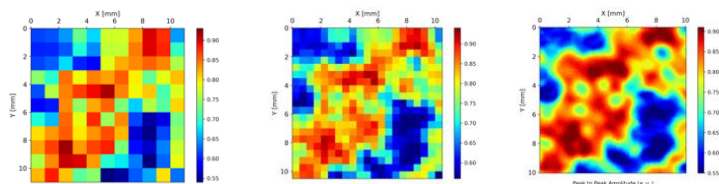
Onyx is the first system in the market designed to provide a full-area non-destructive characterization of Graphene, thin-films, and other 2D materials. Onyx covers the gap between the macro and the nanoscale tools, characterizing from 0,5 mm² to large areas (m²), enhancing the industrialization of research materials.

Compared to other large-area methods, such as the Four Probe method (destructive and with contact), Onyx is capable of measuring the quality of the sample, offering a complete map of its surface for each electrical property that is measured. Spatial resolution in the order of a few hundreds of microns enables the fast characterization of large areas of a sample as opposed to microscopic methods such as Raman, SEM, and TEM.



FEATURES

- ✓ Contactless measurement
- ✓ Ultra-fast full surface characterization (12cm²/min)
- ✓ High resolution. Up to 50 μm
- ✓ No sample preparation needed
- ✓ Powerful & friendly-use graphical interface
- ✓ Versatile equipment: industrial & research

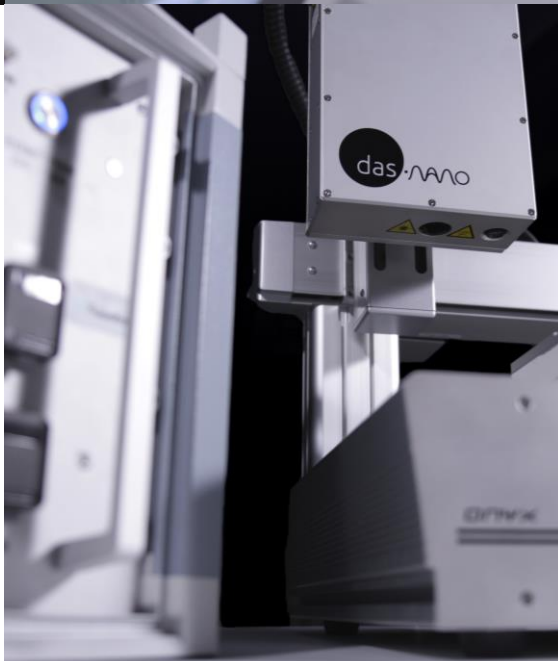


1000 μm

500 μm

50 μm

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ONYX can measure...

- ✓ Sheet conductance/resistance
- ✓ DC sheet conductance/resistance
- ✓ Mobility
- ✓ Carrier density
- ✓ Scattering time
- ✓ Homogeneity

Of a wide variety of materials!

Graphene



- CVD monolayer
- CVD multi-layer
- Epitaxial
- Powder & Flakes
- Inks
- Doped
- Graphene Oxide
- Nanoplatelets

Other thin films

- PEDOT
- Indium Tin Oxide (ITO)
- Indium Gallium Zinc Oxide (IZGO)
- Gallium Nitride (GaN)
- Molybdenum disulphide (MoS₂)
- Ag nanowires
- Titanium nitride (TiN)
- Hexagonal Boron Nitride (hBN)

and many more!



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